

6. (Amended) Apparatus as claimed in claim 1 including one or more microprocessors or other processors which distinguish events in the second field of view from those in the first field of view by means of appropriate pattern recognition algorithms.
7. (Amended) Apparatus as claimed in claim 1 including a test source of radiation arranged to emit radiation onto the lens from outside the first field of view of the apparatus.
8. Apparatus as claimed in claim 7 in which the source illuminates different elements of the detector array at different times.
9. (Amended) Apparatus as claimed in claim 7 further comprising a shielding member for shielding the detector array from the test source.
10. (Amended) Apparatus as claimed in claim 7, further comprising a second reflector arranged to reflect radiation from the test source towards the lens.
11. (Amended) Apparatus as claimed in claim 10 in which the second reflector has one or more concave surfaces.
12. (Amended) Apparatus as claimed in claim 10 in which the second reflector is frusto-conical.
13. (Amended) Apparatus as claimed in claim 10 in which the second reflector has one or more planar reflective surfaces.
14. (Amended) Apparatus as claimed in claim 10 in which the second reflector has cylindrical symmetry about the optical axis of the lens.

15. (Amended) Apparatus as claimed in claim 10 in which the reflector and the second reflector are arranged to reflect radiation onto the whole of the detector array.

16. Apparatus as claimed in claim 7 in which the lens is protected by a window and the source is located inside the window.

17. (Amended) Apparatus as claimed in claim 16 in which the second reflector is located outside the window.

18. (Amended) Apparatus as claimed in claim 7 wherein the test source has means for modulating its output, whereby radiation from the test source can be distinguished from radiation from a scene being viewed.

19. Apparatus as claimed in claim 7 including a microprocessor or other processor for commanding the automatic testing of the apparatus at intervals.

20. Apparatus as claimed in claim 7 in which the test source comprises one or more emitters arranged about the optical axis of the lens.

21. Apparatus as claimed in claim 7 in which the source comprises one or more electrically heated filaments.

22. Apparatus as claimed in claim 7 in which the test source comprises a refractory metal film deposited on a substrate.

23. Apparatus as claimed in claim 16 in which the test source comprises a refractory metal film deposited on a substrate and the substrate is the window.

24. Apparatus as claimed in claim 7 in which the test source is a single continuous radiating element with circular symmetry about the optical axis of the lens.

25. Apparatus as claimed in claim 7 in which the source comprises one or more light emitting diodes.
26. Apparatus as claimed in claim 1 in which the array is an array of thermal detectors.
27. Apparatus as claimed in claim 26 in which the array is an array of pyroelectric detectors.
28. Apparatus as claimed in claim 1 in which the detector array is formed in or mounted on a semiconductor integrated circuit that is used to interrogate it.

REMARKS

This is intended as a full and complete response to the Office Action dated July 3, 2002, having a shortened statutory period for response set to expire on October 3, 2002. Please reconsider the claims pending in the application for reasons discussed below.

The Specification has been amended for clarification. Specifically, the sentence bridging page 1 and page 2 was incomplete. The error was due to mistake and was not intentional. As a result, the paragraph beginning on page 1 has been amended to correct the mistake. Also, the paragraph bridging page 2 and page 3 has been amended to correct informal errors. Applicant believes that no new matter has been introduced.

Claims 1, 6-9, 16 and 19 are rejected under 35 U.S.C. § 102(b) as being anticipated by *Wirth et al.*, U.S. Patent 5,146,073, and claims 2-5, 10-15, 17, and 20-28 stand rejected under § 103 as being unpatentable over *Wirth*. The Examiner states that *Wirth* discloses a radiation detection apparatus comprising a detector array (250) and a lens (105) arranged to provide a single focused image of a distant array, the apparatus